

INTERNATIONAL SEARCH REPORT

International Application No
PCT/AT 03/00018

A. CLASSIFICATION OF SUBJECT MATTER IPC 7 G01R31/308 G01R31/311 G01R31/302 G01N21/17		
According to International Patent Classification (IPC) or to both national classification and IPC		
B. FIELDS SEARCHED Minimum documentation searched (classification system followed by classification symbols) IPC 7 G01R G01N		
Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched		
Electronic data base consulted during the international search (name of data base and, where practical, search terms used) INSPEC, EPO-Internal		
C. DOCUMENTS CONSIDERED TO BE RELEVANT		
Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	DONALDSON W R ET AL: "Integrated circuit tester using interferometric imaging" PROCEEDINGS OF THE UGIM SYMPOSIUM, MICROELECTRONICS EDUCATION FOR THE FUTURE. TWELFTH BIENNIAL UNIVERSITY/GOVERNMENT/INDUSTRY MICROELECTRONICS SYMPOSIUM (CAT. NO.97CH36030), PROCEEDINGS OF THE UGIM SYMPOSIUM, MICROELECTRONICS EDUCATION FOR THE FUTURE, page 107 XP010242546 1997, New York, NY, USA, IEEE, USA ISBN: 0-7803-3790-5 figure 1 <div style="text-align: center; margin-top: 20px;">-/-</div>	1-33
<div style="display: flex; justify-content: space-between;"> <input checked="" type="checkbox"/> Further documents are listed in the continuation of box C. <input checked="" type="checkbox"/> Patent family members are listed in annex. </div>		
* Special categories of cited documents :		
<div style="display: flex; justify-content: space-between;"> <div style="width: 45%;"> <p>*A* document defining the general state of the art which is not considered to be of particular relevance</p> <p>*E* earlier document but published on or after the international filing date</p> <p>*L* document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)</p> <p>*O* document referring to an oral disclosure, use, exhibition or other means</p> <p>*P* document published prior to the international filing date but later than the priority date claimed</p> </div> <div style="width: 45%;"> <p>*T* later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention</p> <p>*X* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone</p> <p>*Y* document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.</p> <p>*Z* document member of the same patent family</p> </div> </div>		
Date of the actual completion of the international search <div style="text-align: center; font-weight: bold;">2 May 2003</div>		Date of mailing of the international search report <div style="text-align: center; font-weight: bold;">19/05/2003</div>
Name and mailing address of the ISA European Patent Office, P.B. 5818 Patentlaan 2 NL - 2280 HV Rijswijk Tel. (+31-70) 340-2040, Tx. 31 651 epo nl, Fax: (+31-70) 340-3016		Authorized officer <div style="text-align: center; font-weight: bold;">Mason, W</div>

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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

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X	DE 100 47 136 A (SCHLUMBERGER TECHNOLOGIES INC) 19 April 2001 (2001-04-19) figure 1	1-33
A	WO 00 57159 A (BOXER CROSS INC) 28 September 2000 (2000-09-28) figures 1A,,5	1-33
A	DE 198 40 725 A (FBH FERDINAND BRAUN INST FUER ;GF MESTECHNIK GMBH (DE)) 18 March 1999 (1999-03-18) figures 1,2	1-33
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A	DE 195 16 842 A (FRAUNHOFER GES FORSCHUNG) 30 November 1995 (1995-11-30) figure 1	1-33
A	YIFAN GUO ET AL: "A practical die stress model and its applications in flip-chip packages" CONFERENCE PROCEEDINGS ARTICLE, vol. 1, 23 May 2000 (2000-05-23), pages 393-399, XP010510427 page 395; figure 3	1-33
A	US 5 414 513 A (LEIB KENNETH G) 9 May 1995 (1995-05-09) figure 1	1-33
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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	US 4 957 367 A (DULMAN LEV) 18 September 1990 (1990-09-18) figure 2	1-33
A	NASSIM K ET AL: "High-resolution interferometry and electronic speckle pattern interferometry applied to the thermomechanical study of a MOS power transistor" MICROELECTRONICS JOURNAL, MACKINTOSH PUBLICATIONS LTD. LUTON, GB, vol. 30, no. 11, November 1999 (1999-11), pages 1125-1128, XP004175865 ISSN: 0026-2692 figure 1	1-33

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Information on patent family members

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